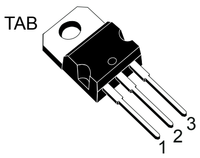
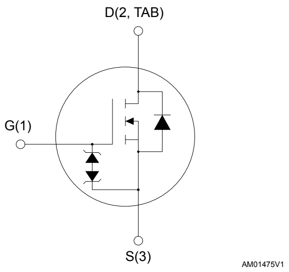
STP20N90K5

Datasheet

N-channel 900 V, 0.21 Ω typ., 20 A MDmesh™ K5 Power MOSFET in a TO-220 package



TO-220



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STP20N90K5	900 V	0.25 Ω	20 A

- Industry's lowest $R_{DS(on)}$ x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Product status link
STP20N90K5

Product summary	
Order code	STP20N90K5
Marking	20N90K5
Package	TO-220
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	±30	V
I_D	Drain current (continuous) at T_C = 25 °C	20	A
I_D	Drain current (continuous) at T_C = 100 °C	13	A
I_D (1)	Drain current (pulsed)	80	A
P_{TOT}	Total power dissipation at T_C = 25 °C	250	W
dv/dt (2)	Peak diode recovery voltage slope	4.5	V/ns
dv/dt (3)	MOSFET dv/dt ruggedness	50	
T_j	Operating junction temperature range	-55 to 150	°C
T_{stg}	Storage temperature range		

1. *Pulse width limited by safe operating area.*
2. *I_{SD} ≤ 20A, di/dt ≤ 100 A/µs; V_{DS} peak ≤ $V_{(BR)DSS}$, V_{DD}= 450 V.*
3. *V_{DS} ≤ 720 V.*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	0.5	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient	62.5	°C/W

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	6.5	A
E_{AS}	Single pulse avalanche energy (starting T_j = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	500	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 4. On/off-state

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	900			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 900 V			1	µA
		V_{GS} = 0 V, V_{DS} = 900 V T_C = 125 °C (1)			50	µA
I_{GSS}	Gate body leakage current	V_{DS} = 0 V, V_{GS} = ±20 V			±10	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 100 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 10 A		0.21	0.25	Ω

1. *Defined by design, not subject to production test*

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	1500	-	pF
C_{oss}	Output capacitance		-	120	-	pF
C_{rss}	Reverse transfer capacitance		-	1	-	pF
$C_{o(er)}$ (1)	Equivalent capacitance energy related	V_{DS} = 0 to 720 V, V_{GS} = 0 V	-	78	-	pF
$C_{o(tr)}$ (2)	Equivalent capacitance time related			220	-	pF
R_g	Intrinsic gate resistance	f = 1 MHz, I_D = 0 A	-	3.7	-	Ω
Q_g	Total gate charge	V_{DD} = 720 V, I_D = 20 A V_{GS} = 0 to 10 V (see Figure 14. Test circuit for gate charge behavior)	-	40	-	nC
Q_{gs}	Gate-source charge		-	14	-	nC
Q_{gd}	Gate-drain charge		-	17	-	nC

1. *$C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*
2. *$C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD}= 450 V, I_D = 10 A, R_G = 4.7 Ω, V_{GS} = 10 V (see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	20.2	-	ns
t_r	Rise time		-	13.5	-	ns
$t_{d(off)}$	Turn-off delay time		-	64.7	-	ns
t_f	Fall time		-	16	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		20	A
I_{SDM} (1)	Source-drain current (pulsed)		-		80	A
V_{SD} (2)	Forward on voltage	I_{SD} = 20 A, V_{GS} = 0 V	-		1.5	V
t_{rr}	Reverse recovery time	I_{SD} = 20 A, di/dt = 100 A/µs, V_{DD} = 60 V (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	517		ns
Q_{rr}	Reverse recovery charge		-	11.4		µC
I_{RRM}	Reverse recovery current		-	44		A
t_{rr}	Reverse recovery time	I_{SD} = 20 A, di/dt = 100 A/µs V_{DD} = 60 V, T_j = 150 °C (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	674		ns
Q_{rr}	Reverse recovery charge		-	14		µC
I_{RRM}	Reverse recovery current		-	41.6		A

1. *Pulse width limited by safe operating area*
2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%*

Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	I_{GS}= ±1 mA, I_D= 0 A	30	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection,thus eliminating the need for additional external componentry.

2.1 Electrical characteristics curves

Figure 1. Safe operating area

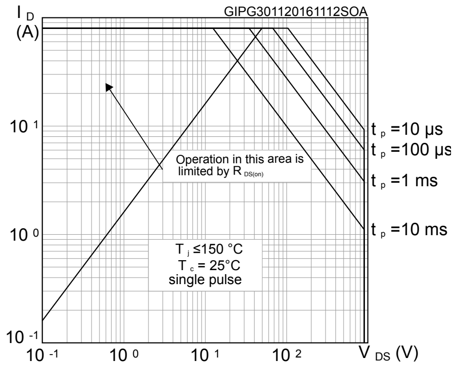


Figure 2. Thermal impedance

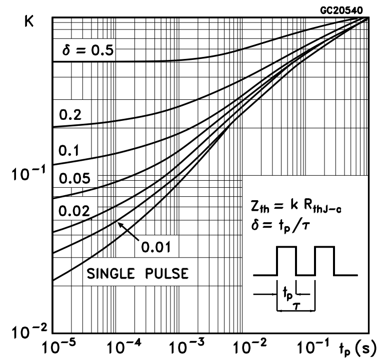


Figure 3. Output characteristics

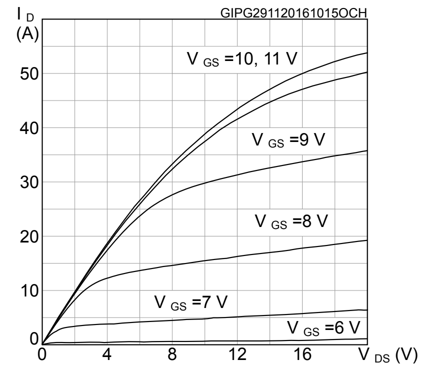


Figure 4. Transfer characteristics

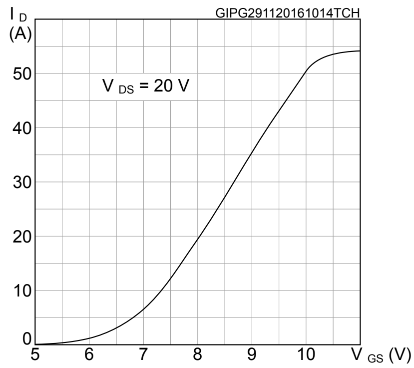


Figure 5. Normalized $V_{(BR)DSS}$ vs temperature

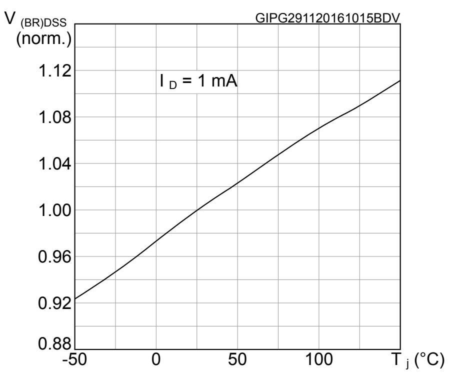


Figure 6. Static drain-source on-resistance

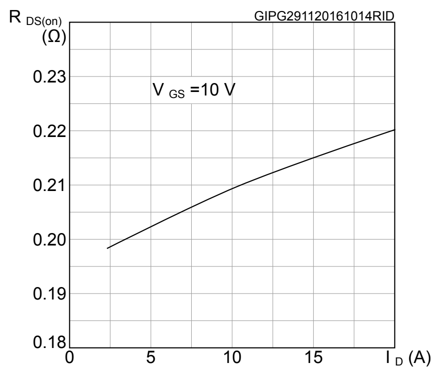


Figure 7. Gate charge vs gate-source voltage

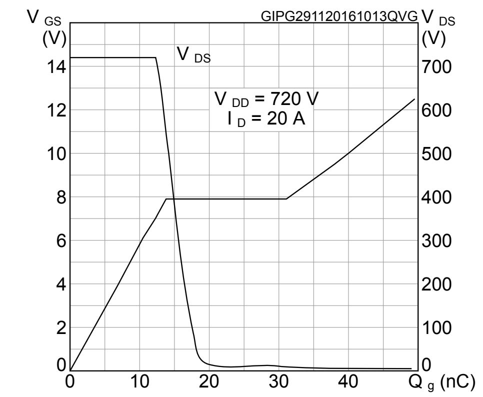


Figure 8. Capacitance variation

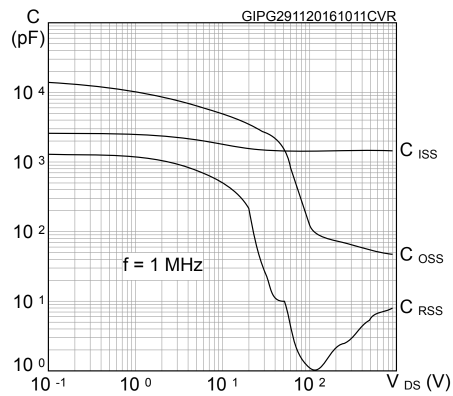


Figure 9. Normalized gate threshold voltage vs temperature

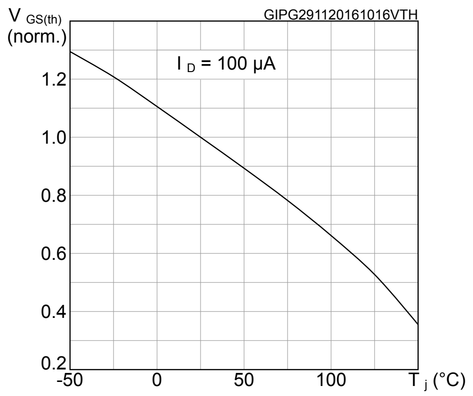


Figure 10. Normalized on-resistance vs temperature

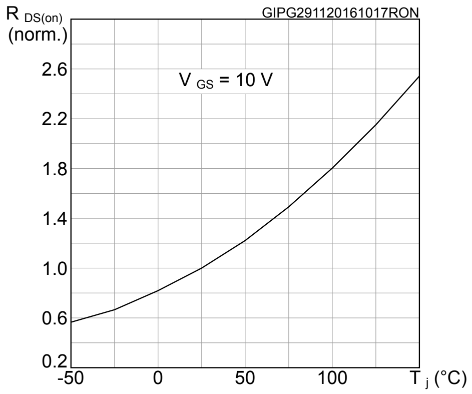


Figure 11. Maximum avalanche energy vs. starting T_J

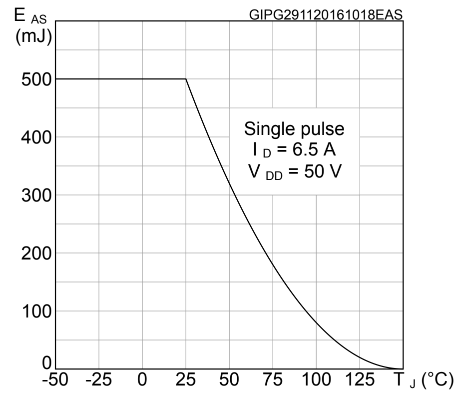
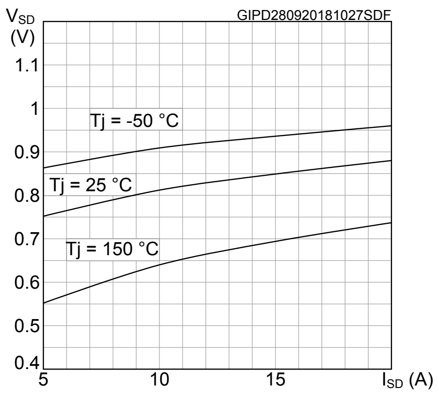


Figure 12. Source-drain diode forward characteristics



3 Test circuits

Figure 13. Test circuit for resistive load switching times

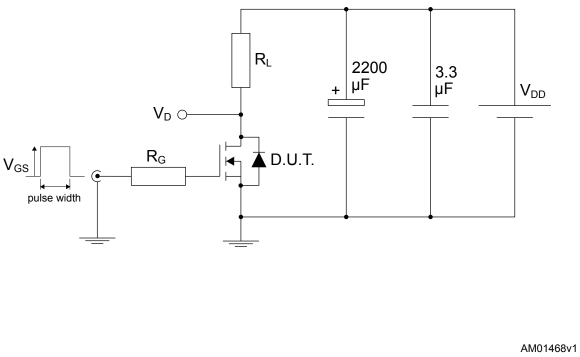


Figure 14. Test circuit for gate charge behavior

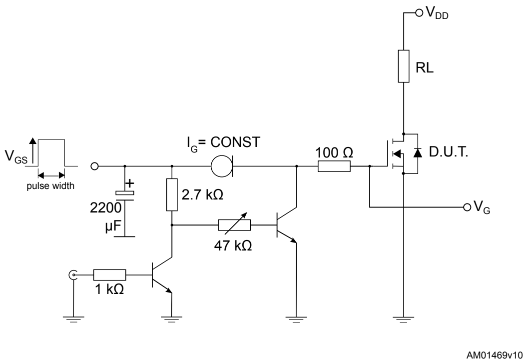


Figure 15. Test circuit for inductive load switching and diode recovery times

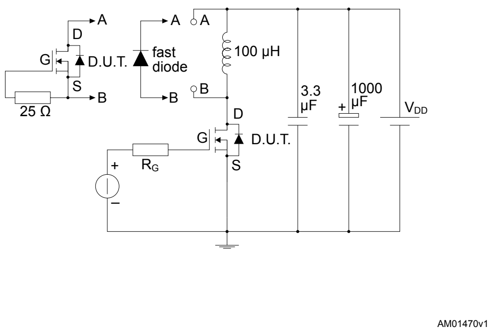


Figure 16. Unclamped inductive load test circuit

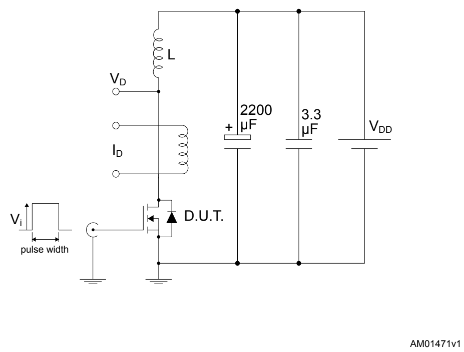


Figure 17. Unclamped inductive waveform

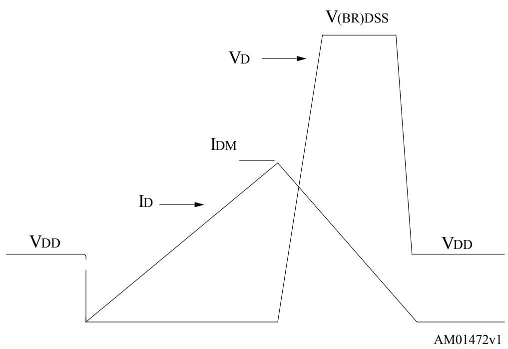
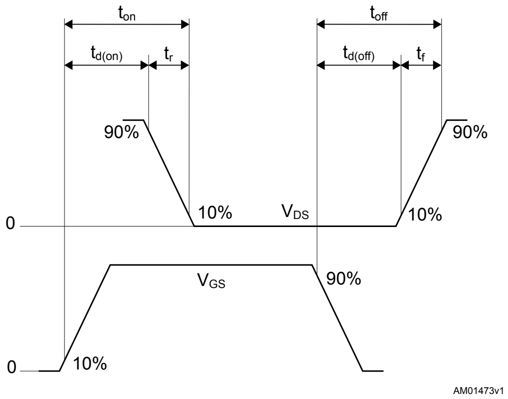


Figure 18. Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220 type A package information

Figure 19. TO-220 type A package outline

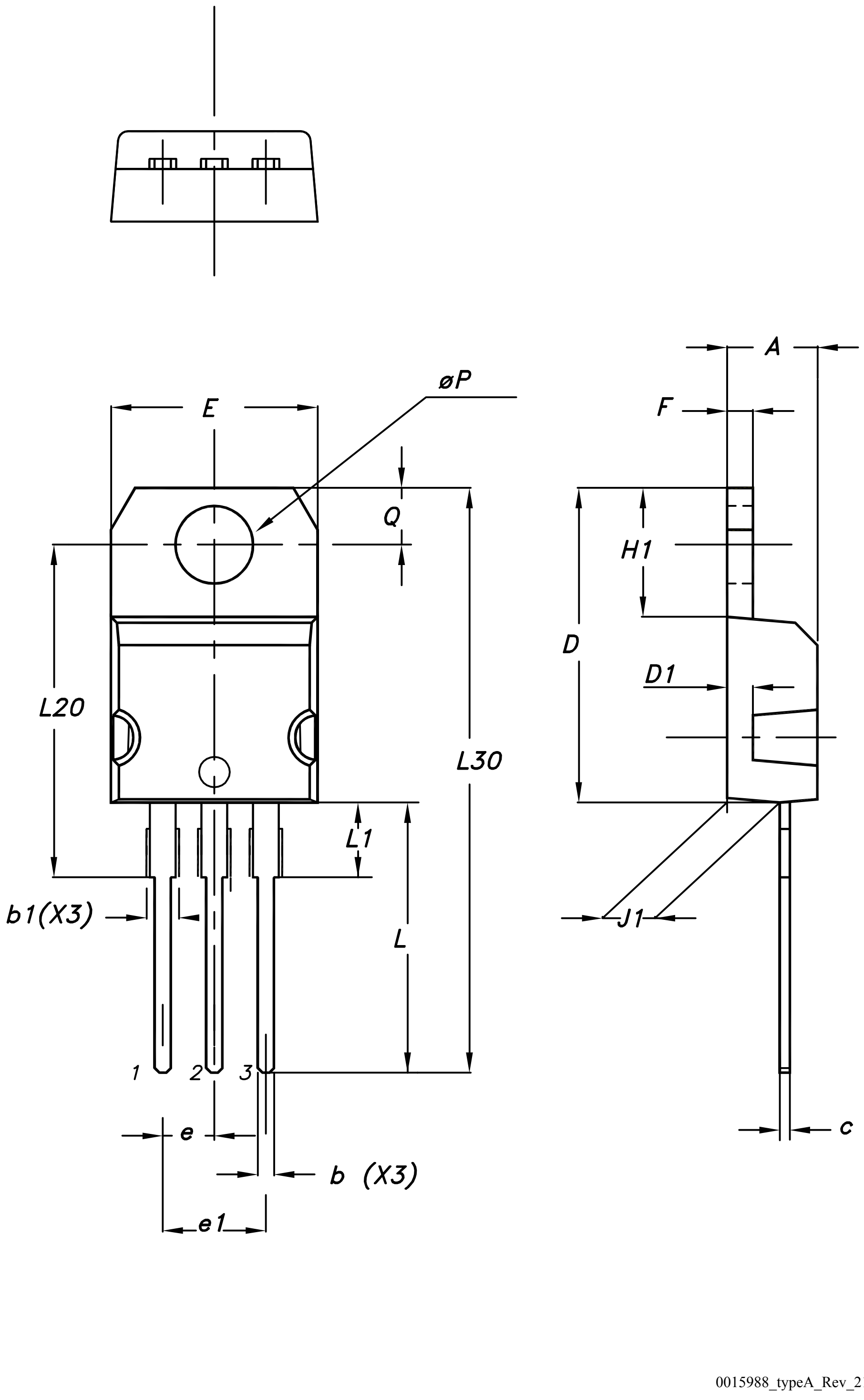


Table 9. TO-220 type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95

Revision history

Table 10. Document revision history

Date	Revision	Changes
10-May-2016	1	First release.
01-Dec-2016	2	Modified: title and $R_{DS(on)}$ value in cover page Modified *Table 4: "Avalanche characteristics", Table 5: "On/off-state", Table 6: "Dynamic", Table 7: "Switching times" and Table 8: "Sourcedrain diode"* Added *Section 2.1: "Electrical characteristics (curves)"* Modified *Section 3: "Test circuits"* Datasheet promoted from preliminary data to production data Minor text changes
24-Jan-2017	3	Modified Table 6: "Dynamic". Minor text changes.
05-Oct-2018	4	Removed maturity status indication from cover page. Added Figure 12. Source-drain diode forward characteristics. Minor text changes.

Contents